

EAST SEARCH

9/21/2003

L#	Hits	Search String	Databases
S1	494501	(chemical or petrochemical or manufacturing) near2 process\$2	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S2	573	((chemical or petrochemical or manufacturing) near2 process\$2) with (process near2 model\$2 or process near2 model\$2) same (process near2 model\$2 or process near2 model\$2)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S3	785	((chemical or petrochemical or manufacturing) near2 process\$2) same (process near2 model\$2 or process near2 model\$2)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S4	785	S2 or S3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S5	73	S4 and (integrated near2 model\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S6	5	S4 and (symbolic near2 (model\$3 or language))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S17	85	S4 and (process with environment with model\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S18	0	S4 and ((log or logging) with (assumption or (model near2 transformation)))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S7	20	S4 and (symbolic near2 (manipulation or representation or description))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S22	1	S4 and (rate near2 change) with (mass near2 (vapor or liquid)))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S8	2	S4 and (ancestor near2 model\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S23	52	S4 and (rate near2 change)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S24	10	S4 and (energy near2 (vapor or liquid))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S25	6	S4 and ((pressure or thermal) near2 equilibrium)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S27	4	S4 and ("equal pressure" or "gas law" or "volume correlation")	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S29	207	S9 or S13	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S30	153	S28 and S29	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S9	132	S4 and ((specific or environment) near2 model\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S31	306	S28 or S30	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S32	20	S31 and (S6 or S7)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S33	2	S31 and S8	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S34	3	S4 and (formal near2 language)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S38	9	S4 and (model near2 transformation)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S40	2	S31 and S20	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S41	3	S31 and S21	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S45	4	S31 and S27	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S10	33	S4 and ((formal near2 language) or (equation near2 based))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S11	8	S4 and (Mathematica or Axiom or MAPLE or ADIFOR)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S12	35	S4 and (generic near2 (model\$3 or component))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S13	142	S4 and (model\$3 with (assumption or environment))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S14	2	S4 and (component near2 specific near2 model)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S15	65	S4 and (component near2 model)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S16	9	S4 and (environment near2 independent)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S19	75	S4 and (log or logging)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S20	2	S4 and (flash near2 column)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S21	3	S4 and (parameter near2 representation)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S26	6	S4 and ((vapor or liquid) near2 (enthalpy or heat))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S28	306	S5 or S6 or S7 or S8 or S10 or S11 or S12 or S14 or S15 or S16 or S17 or S19 or S20 or S21	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S35	3	S31 and S34	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S36	8	S31 and S11	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S37	85	S31 and S17	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB

S39	7	S31 and S38	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S42	3	S4 and (mass near2 (vapor or liquid))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S44	6	S31 and S25	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S43	10	S31 and (S24 or S42)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S46	573	((chemical or petrochemical or manufacturing) near2 process\$2) with (process near2 model\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S48	785	S46 or S47	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S49	73	S48 and (integrated near2 model\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
S51	20	S48 and (symbolic near2 (manipulation or representation or description))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
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S71	306	S49 or S50 or S51 or S52 or S54 or S55 or S56 or S58 or S59 or S60 or S61 or S62 or S63 or S63 c	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB
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Results of search set S91:	Document Kind	Code/Title	Issue Date	Current OR	Abstract
	US	20060195213 A1	Method of operating an advanced process controller by dynamically adapting hierarchy levels	20060831	700/108
	US	20060190913 A1	Method and apparatus for identifying a manufacturing problem area in a layout using a grid	20060824	716/19
	US	20060190223 A1	SAMPLE PROBABILITY OF FAULT FUNCTION DETERMINATION USING CRITICAL DEFECT	20060824	703/2
	US	20060190222 A1	PROBABILITY OF FAULT FUNCTION DETERMINATION USING CRITICAL DEFECT SIZE 1	20060824	703/2
	US	20060178528 A1	Method of controlling acetic acid process	20060810	562/519
	JPS	20050172427 A1	Method and apparatus for retrofitting existing real time control systems for monitoring, control	20060803	436/55

US 20060150129 A1	Stochastic analysis process optimization for integrated circuit design and manufacture	20060706 716/4
US 20060136138 A1	Creation and maintenance of a history list in a method and apparatus for integrated modeling	20060622 702/19
US 20060124156 A1	Carbon dioxide snow apparatus	20060615 134/99.1
US 20060117654 A1	Bench scale apparatus to model and develop biopharmaceutical cleaning procedures	20060608 47/58.1SC
US 20060117067 A1	System and method for interactive visual representation of information content and relationships	20060601 707/104.1
US 20060111804 A1	Multivariate control of semiconductor processes	20060525 700/110
US 20060106737 A1	Search for similar or sheet metal part models	20060518 707/2
US 20060106485 A1	Enhanced digital process design methodology for process centric CAD systems	20060518 700/182
US 20060103318 A1	Apparatus and method for dynamic diagnostic testing of integrated circuits	20060518 324/228
US 20060101370 A1	METHOD FOR IMPROVING OPTICAL PROXIMITY CORRECTION	20060511 716/19
US 20060100873 A1	CIRCUIT STATISTICAL MODELING FOR PARTIALLY CORRELATED MODEL PARAMETER	20060511 704/256.2
US 20060074603 A1	Customer support system and method of customer support	20060406 702/188
US 20060074599 A1	Application of abnormal event detection technology to olefins recovery trains	20060406 702/185
US 20060074598 A1	Application of abnormal event detection technology to hydrocracking units	20060406 702/185
US 20060073013 A1	Application of abnormal event detection technology to fluidized catalytic cracking unit	20060406 416/35
US 20060073013 A1	Defect location identification for microdevice manufacturing and test	20060330 714/33
US 20060069988 A1	Reuse of manufacturing process design models as part of a diagnostic system	20060330 703/22
US 20060069541 A1	System and method for abnormal event detection in the operation of continuous industrial process	20060316 700/29
US 20060015294 A1	Data collection and analysis system	20060119 702/183
US 20060014394 A1	Process for low temperature, dry etching, and dry planarization of copper	20060119 438/710
US 20050272640 A1	Method and apparatus for glucose control and insulin dosing for diabetics	20051208 514/3
US 20050270199 A1	Method for designing mixed signal integrated circuits and configurable synchronous digital logic	20051208 341/120
US 20050268256 A1	Modeling resolution enhancement processes in integrated circuit fabrication	20051201 716/4
US 20050267723 A1	Physicochemical process modeling system	20051201 703/11
US 20050261888 A1	Time dependent process parameters for integrated process and product engineering	20051124 703/22
US 20050261887 A1	Time dependent process parameters and engineering change number conflict report	20051124 703/22
US 20050261791 A1	Interfaces from external systems to time dependent process parameters in integrated processes	20051124 700/97
US 20050235246 A1	Use of models in integrated circuit fabrication	20051020 716/21
US 20050234568 A1	Predictive modeling of machining line variation	20051020 700/159
US 20050228511 A1	Computer-implemented system and method for measuring and improving manufacturing process	20051013 700/28
US 20050209834 A1	Horizontally structured CAD/CAM modeling->vertical to horizontal conversion	20050922 703/2
US 20050187747 A1	Method and apparatus for improved simulation of chemical and biochemical reactions	20050825 703/11
US 20050187746 A1	Method and apparatus for improved modeling of chemical and biochemical reactions	20050825 703/11
US 20050187745 A1	Method and apparatus facilitating communication with a simulation environment	20050825 703/11
US 20050187717 A1	Method and apparatus for integrated modeling, simulation and analysis of chemical and biocatalytic processes	20050825 702/19
US 20050235246 A1	Parametric universal nonlinear dynamics approximator and use	20050825 700/29
US 20050181342 A1	Medical training simulator including contact-less sensors	20050818 434/262
US 20050159934 A1	Integrated modeling through symbolic manipulation	20050721 703/2
US 20050154477 A1	Kiln control and upset recovery using a model predictive control in series with forward chainring	20050714 700/37
US 20050132306 A1	Characterization and reduction of variation for integrated circuits	20050616 716/1
US 20050120010 A1	System and method for determining costs within an enterprise	20050602 707/3
US 20050065767 A1	Closed loop integration of digital models of in silico systems and experimental procedures	20050324 703/22
US 20050065626 A1	Material reservation distribution system and method	20050324 700/97
US 20050060584 A1	Trusted infrastructure support systems, methods and techniques for secure electronic commerce	20050317 726/4
US 20050045029 A1	Selective separation of fluid compounds utilizing a membrane separation process	20050303 95/46
US 20050037522 A1	Dummy fill for integrated circuits	20050217 438/8
US 20050010319 A1	System and method for validating and visualizing APC assisted semiconductor manufacturing	20050113 700/121
US 20050004687 A1	Apparatus and method of controlling multi-input-single-output systems	20050106 700/44

US 20040256230 A1	Microfluidic devices for transverse electrophoresis and isoelectric focusing	20041223 204/450
US 20040230411 A1	Apparatus and methods for predicting properties of processed material	20041118 703/6
US 20040220691 A1	Method and apparatus for constructing crowns, bridges and implants for dental use	20041104 700/98
US 20040220689 A1	Sensor placement and control design for distributed parameter systems	20041104 700/97
US 20040210429 A1	Apparatus and methods for performing process simulation using a hybrid model	20041021 703/9
US 20040182786 A1	Purification of fluid compounds utilizing a distillation - membrane separation process	20040923 210/640
US 20040167763 A1	Information processing method for evaluating biochemical pathway models using clinical data	20040826 703/11
US 20040154985 A1	Wet and dry weather water flows disinfection system	20040812 210/85
US 20040153296 A1	Horizontally structured CAD/CAM coordinate system	20040805 703/2
US 20040153202 A1	Horizontally structured manufacturing process modeling - across file feature operability	20040805 700/182
US 20040153201 A1	Horizontally structured CAD/CAM coordinate system for manufacturing design	20040805 700/182
US 20040153200 A1	Horizontally structured manufacturing process modeling - exterior linked representational emb	20040805 700/182
US 20040153197 A1	Modeling an abrasive process to achieve controlled material removal	20040805 700/164
US 20040148047 A1	Hierarchical methodology for productivity measurement and improvement of production systems	20040729 700/100
US 20040139419 A1	Minimization of microelectronic interconnect thickness variations	20040715 716/20
US 20040130276 A1	System and method of applying adaptive control to the control of particle accelerators with va	20040708 315/501
US 20040128003 A1	SYSTEM AND METHOD FOR MODEL BASED CONTROL OF A NEURAL NETWORK	20040701 700/31
US 20040128002 A1	SYSTEM AND METHOD FOR MODEL BASED CONTROL OF A CHEMICAL PROCESS	20040701 700/31
US 20040123129 A1	Trusted infrastructure support systems, methods and techniques for secure electronic commerce	20040624 713/193
US 20040121495 A1	Dynamic adaptive sampling rate for model prediction	20040624 438/14
US 20040117040 A1	System and method of adaptive control of processes with varying dynamics	20040617 700/29
US 20040102955 A1	Method for regulating a property of a product derived from a chemical transformation	20040527 703/2
US 20040099213 A1	Spatially programmable microelectronics process equipment using segmented gas injection	20040527 118/715
US 200400992107 A1	Probability constrained optimization for electrical fabrication control	20040513 700/108
US 20040088149 A1	Method and apparatus for performing OPC using model curvature	20040506 703/13
US 20040088065 A1	Cooperative smart items	20040506 700/95
US 20040083452 A1	Method and system for predicting multi-variable outcomes	20040429 717/109
US 20040083028 A1	Process control using on-line instrumentation and process models	20040429 700/269
US 20040076944 A1	Supervised learning in the presence of null data	20040422 434/433
US 20040068342 A1	Method of designing and manufacturing rubber process tooling using an interface to a CAD/C	20040408 700/182
US 20040068332 A1	Stochastic modeling of spatial distributed sequences	20040408 700/51
US 20040034555 A1	Hierarchical methodology for productivity measurement and improvement of complex product	20040219 705/7
US 20040034517 A1	DEVICE MODELING FOR PROXIMITY EFFECTS	20040219 703/14
US 20040028253 A1	Detoxification of solid freeform fabrication materials	20040212 381/322
US 20040015335 A1	Method, system and medium for controlling manufacturing process using adaptive models	20040122 703/2
US 20030237064 A1	Characterization and verification for integrated circuit designs	20031225 716/5
US 20030229881 A1	Adjustment of masks for integrated circuit fabrication	20031211 716/19
US 20030229880 A1	Test masks for lithographic and etch processes	20031211 716/19
US 20030229875 A1	Use of models in integrated circuit fabrication	20031211 716/10
US 20030229868 A1	Electronic design for integrated circuits based process related variations	20031211 716/5
US 20030229412 A1	Electronic design for integrated circuits based on process related variations	20031211 700/121
US 20030229410 A1	Integrated circuit metrology	20031211 700/109
US 2003020064 A1	One-dimensional modeling of the manufacture of multi-layered material	20031023 703/2
US 20030195708 A1	Method for analyzing an unknown material as a blend of known materials calculated so as to	20031016 702/22
US 20030149502 A1	Method and system for creating a tooling master model for manufacturing parts	20030807 700/98
US 20030149498 A1	Method and system for reverse and re-engineering parts	20030807 700/97
US 20030146761 A1	Apparatus and method for dynamic diagnostic testing of integrated circuits	20030807 324/501
US 20030144758 A1	System and method for integrating geometric models	20030731 700/104

US 20030113620 A1	Patient monitoring system employing array of force sensors on a bedsheets or similar substrat	20030724 73/862.41
US 20030120372 A1	System, method and computer program product for mapping data of multi-database origins	20030626 700/108
US 20030115005 A1	System and method for controlling critical dimension in a semiconductor manufacturing process	20030619 702/84
US 20030114950 A1	System, method and computer program product for mapping data of multi-database origins	20030619 700/108
US 20030100972 A1	Reusable software components for invoking computational models	20030529 700/121
US 20030098292 A1	Process for low temperature, dry etching, and dry planarization of copper	20030529 216/78
US 20030097243 A1	Method and system for operating a hydrocarbon production facility	20030522 703/2
US 20030097197 A1	Method, system and storage medium for enhancing process control	20030522 700/108
US 20030093762 A1	Large scale process control by driving factor identification	20030515 7/16/2
US 20030074174 A1	Manufacturing methods and systems for rapid production of hearing-aid shells	20030417 703/13
US 20030061015 A1	Stochastic modeling of time distributed sequences	20030327 703/2
US 20030046130 A1	System and method for real-time enterprise optimization	20030306 705/7
US 20030033041 A1	System and method for producing an assembly by directly implementing three-dimensional cx	20030213 700/98
US 20030028265 A1	Kiln/cooler control and upset recovery using a combination of model predictive control and ex	20030206 700/31
US 20030023403 A1	Process for estimating random error in chemical and biological assays when random error dif	20030130 702/179
US 20030023386 A1	Metabolome profiling methods using chromatographic and spectroscopic data in pattern reco	20030130 702/19
US 20030005747 A1	Method for detecting and correcting sensor failure in oil and gas production system	20030109 731.16
US 20030004596 A1	Horizontally-structured CAD/CAM modeling for virtual concurrent product and process design	20030102 700/98
US 20020199123 A1	Security architecture for a process control platform executing applications	20021226 726/3
US 20020198320 A1	Supervisory process control and manufacturing information system application having a layer	20021226 718/100
US 20020198697 A1	Universal epistemological machine (a.k.a. android)	20021226 704/1
US 20020198816 A1	Manufacturing scheduling process with improved modeling, scheduling and editing capabilities	20021226 700/99
US 20020194393 A1	Method of determining causal connections between events recorded during process executio	20021219 719/318
US 20020171176 A1	Detoxification of solid freeform fabrication materials	20021121 264/401
US 20020165636 A1	Systems and methods for metrology recipe and model generation	20021107 700/121
US 20020156757 A1	Electronic product design system	20021024 707/1
US 20020156542 A1	Methods, devices and systems for monitoring, controlling and optimizing processes	20021024 700/30
US 20020152000 A1	Automated horizontally structured manufacturing process design modeling	20021017 700/98
US 20020136622 A1	Method and apparatus for monitoring the coating on particle during manufacturing of a pharm	20020926 427/8
US 20020133803 A1	Enhancement to horizontally-structured CAD/CAM modeling	20020919 717/104
US 20020133267 A1	Enhancement to horizontally structured manufacturing process modeling	20020919 700/182
US 20020133266 A1	Horizontally structured manufacturing process modeling for alternate operations, large parts &	20020919 700/182
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US 20020133253 A1	Horizontally-structured CAD/CAM modeling for virtual fixture and tooling processes	20020919 700/98
US 20020133252 A1	Horizontally structured manufacturing process modeling for fixtures and tooling	20020919 700/97
US 20020111782 A1	Method for simulating chemical reactions	20020815 703/12
US 20020103548 A1	Computer method and apparatus for optimized controller in a non-linear process	20020801 700/30
US 20020077719 A1	Variable parameter controls for semiconductor processes	20020620 700/117
US 20020072872 A1	Method for diagnosing process parameter variations from measurements in analog circuits	20020613 702/117
US 20020072828 A1	Computer method and apparatus for constraining a non-linear approximator of an empirical p	20020613 700/269
US 20020059003 A1	System, method and computer program product for mapping data of multi-database origins	20020516 700/9
US 20020052858 A1	Method and tool for data mining in automatic decision making systems	20020502 706/15
US 20020038163 A1	Apparatus and method for managing and distributing design and manufacturing information t	20020328 700/165
US 20010025232 A1	Hybrid linear-neural network process control	20010927 703/13
US 20010020395 A1	Patient monitoring system employing array of force sensors on a bedsheets or similar substrat	20010913 73/862.041
US 7110956 B1	Capability predictor	20060919 705/7
US 7110849 B2	Horizontally-structured CAD/CAM modeling for virtual fixture and tooling processes	20060919 700/159
US 7106897 B1	Universal spatial pattern recognition system	20060912 362/145

US 7099804 B2	Automated horizontally structured manufacturing process design modeling	20060829 703/1
US 7089081 B2	Modeling an abrasive process to achieve controlled material removal	20060808 700/175
US 7089075 B2	Systems and methods for metrology recipe and model generation	20060808 700/121
US 7079808 B2	Horizontally-structured modeling for analysis	20060718 700/98
US 7070694 B2	Purification of fluid compounds utilizing a distillation - membrane separation process	20060704 210/640
US 7064076 B2	Process for low temperature, dry etching, and dry planarization of copper	20060620 438/714
US 7039475 B2	System and method of adaptive control of processes with varying dynamics	20060502 700/31
US 7037172 B1	Advanced wafer planarizing	20060502 45/15
US 7031782 B2	Material reservation distribution system and method	20060418 700/95
US 7008300 B1	Advanced wafer refining	20060307 45/141
US 7006889 B2	Sensor placement and control design for distributed parameter systems	20060228 700/204
US 6996245 B2	Detoxification of solid freeform fabrication materials	20060207 381/322
US 6986802 B2	Selective separation of fluid compounds utilizing a membrane separation process	20060117 95/46
US 6986598 B1	Wafer refining	20060117 45/15
US 6985793 B2	Horizontally structured CAD/CAM coordinate system for manufacturing design	20060110 700/182
US 6975915 B2	Cooperative smart items	200512/13 700/108
US 6970757 B1	Method and apparatus for updating control state variables of a process control model based on	20051129 700/108
US 6968303 B1	Automated system for extracting and combining tool trace data and wafer electrical test (WET)	20051122 703/13
US 6961626 B1	Dynamic offset and feedback threshold	20051101 700/31
US 6959224 B2	Probability constrained optimization for electrical fabrication control	20051025 700/97
US 6952688 B1	Knowledge-engineering protocol-suite	20051004 706/45
US 6950719 B2	Horizontally structured manufacturing process modeling: across file feature operability	20050927 700/182
US 6947883 B1	Method for designing mixed signal integrated circuits and configurable synchronous digital nc	20050920 703/23
US 6946157 B2	Method and apparatus for monitoring the coating on particle during manufacturing of a pharm	20050920 4272.15
US 6922599 B2	System and method for producing an assembly by directly implementing three-dimensional &	20050726 700/98
US 6915172 B2	Method, system and storage medium for enhancing process control	20050705 700/31
US 6904328 B2	Large scale process control by driving factor identification	20050607 700/97
US 6889177 B1	Large area pattern erosion simulator	20050503 703/2
US 6883153 B2	Minimization of microelectronic interconnect thickness variations	20050419 716/6
US 6876894 B1	Forecast test-out of probed fabrication by using dispatching simulation method	20050405 700/100
US 6859031 B2	Apparatus and method for dynamic diagnostic testing of integrated circuits	20050222 324/233
US 6856856 B1	Resin transfer molding	20050215 700/197
US 6856842 B2	Method and system for creating a tooling master model for manufacturing parts	20050215 700/31
US 6840117 B2	Patient monitoring system employing array of force sensors on a bedsheet or similar substrate	20050111 73/862.041
US 6839560 B2	Horizontally structured manufacturing process modeling for fixtures and tooling	20050104 700/159
US 6839599 B2	Kiln/cooler control and upset recovery using a combination of model predictive control and ex	20050104 700/79
US 6821910 B2	Spatially programmable microelectronics process equipment using segmented gas injection &	20041123 438/758
US 6807583 B2	Method of determining causal connections between events recorded during process executio	20041019 719/318
US 6804568 B1	3-D CAD/CAM data transfer method, 3-D CAD apparatus, 3-D CAD/CAM	20041012 700/98
US 6802045 B1	Method and apparatus for incorporating control simulation environment	20041005 716/2
US 6775585 B2	Method and designing and manufacturing rubber process tooling using an interface to a CAD	20040810 700/182
US 6775581 B2	Horizontally-structured CAD/CAM modeling for virtual concurrent product and process design	20040810 700/98
US 6772082 B2	Method for detecting and correcting sensor failure in oil and gas production system	20040803 702/116
US 6772044 B1	Sensor placement and control design for distributed parameter systems	20040803 700/204
US 6763277 B1	Method and apparatus for proactive dispatch system to improve line balancing	20040713 700/100
US 6757579 B1	Kalman filter state estimation for a manufacturing system	20040629 700/108
US 6754556 B1	Horizontally structured manufacturing process modeling; enhancement to multiple master pro	20040622 700/182
US 6741998 B2	System, method and computer program for mapping a hierarchical display of process data of	20040525 707/102

US 6738682 B1	Method and apparatus for scheduling based on state estimation uncertainties	20040518 700/100
US 6735489 B1	Horizontally structured manufacturing process modeling	20040511 700/95
US 6725230 B2	System, method and computer program for assembling process data of multi-database origin	20040420 707/102
US 6719615 B1	Versatile wafer refining	20040413 451/41
US 6708073 B1	Lot specific process design methodology	20040316 700/121
US 6691127 B1	Storage and retrieval of process capability and guidance information, and computer media therefor	20040210 707/102
US 6689754 B1	Method for optimizing the layout and operation of a reduction method	20031230 75/375
US 6662116 B2	Method for analyzing an unknown material as a blend of known materials calculated so as to detoxify or solidify	20031209 702/22
US 6660208 B2	Detoxification of solid freeform fabrication materials	20031209 264/401
US 6656568 B1	Trusted infrastructure support system, methods and techniques for secure electronic commerce	20031202 713/193
US 6654649 B2	Computer method and apparatus for optimized controller in a non-linear process	20031125 700/31
US 6643616 B1	Integrated device structure prediction based on model curvature	20031104 703/13
US 6643615 B1	Product design process with included producibility information	20031104 703/16
US 6643596 B2	System and method for controlling critical dimension in a semiconductor manufacturing process	20031104 702/84
US 6631630 B1	Hydroforming of composite materials	20031014 72/60
US 6625785 B2	Method for diagnosing process parameter variations from measurements in analog circuits	20030923 716/4
US 6620568 B1	Deriving statistical device models from electrical test data	20030506 703/2
US 6605030 B1	Method and apparatus for monitoring controller performance using statistical process control	20030506 700/108
US 6556959 B1	Method and apparatus for updating a manufacturing model based upon fault data relating to a manufacturing process	20030429 703/12
US 6556884 B1	Method and apparatus for interfacing a statistical process control system with a manufacturing system	20030429 700/121
US 6549631 B1	Pressure transducing assembly	20030415 383/111
US 6546813 B2	Patient monitoring system employing array of force sensors on a bedsheets or similar substrates	20030415 73/862.041
US 6546364 B1	Method and apparatus for creating adaptive workflows	20030408 703/22
US 6535795 B1	Method for chemical addition utilizing adaptive optimization	20030318 700/266
US 6483938 B1	System and method for classifying an anomaly	20021119 382/149
US 6434441 B1	Designing and making an article of manufacture	20020813 700/98
US 6425112 B1	Auto correction of error checked simulated printed images	20020723 716/5
US 6415196 B1	Manufacturing scheduling process with improved modeling, scheduling and editing capabilities	20020702 700/100
US 6411862 B1	Apparatus and method for managing and distributing design and manufacturing information in a distributed environment	20020625 700/182
US 6366822 B1	Statistical process window design methodology	20020402 700/31
US 6356861 B1	Deriving statistical device models from worst-case files	20020312 703/2
US 6333768 B1	Method and apparatus for designing a manufacturing process for sheet metal parts	20020305 700/97
US 6347256 B1	Manufacturing process modelling techniques	20020212 700/100
US 6343261 B1	Apparatus and method for automatically diagnosing a technical system with efficient storage	20020129 702/183
US 6341372 B1	Universal machine translator of arbitrary languages	20020122 717/136
US 6327514 B1	Apparatus and method for managing and distributing design and manufacturing information in a distributed environment	20011204 700/145
US 6321133 B1	Method and apparatus for order promising	20011120 700/100
US 6298470 B1	Method for efficient manufacturing of integrated circuits	20011002 716/4
US 6292582 B1	Method and system for identifying defects in a semiconductor	20010918 382/149
US 6279009 B1	Dynamic creation of workflows from deterministic models of real world processes	20010821 707/103R
US 6278962 B1	Hybrid linear-neural network process control	20010821 703/13
US 6228901 B1	Methods for creating aggregate plans useful in manufacturing environments	20010821 700/99
US 6228927 B1	System and method for designing integrated circuits	20010731 700/97
US 6226655 B1	Computer-implemented value management tool for an asset intensive manufacturer	20010724 705/400
US 6263255 B1	Advanced process control for semiconductor manufacturing	20010717 700/121
US 6249598 B1	Solder testing apparatus	20010619 382/150
US 6246787 B1	System and method for knowledgebase generation and management	20010612 382/141
US 6233545 B1	Universal machine translator of arbitrary languages utilizing epistemic moments	20010515 704/2

US 6219586 B1	Apparatus and method for managing and distributing design and manufacturing information to a manufacturing system	20010417 700/182
US 6212441 B1	Apparatus and method for managing and distributing design and manufacturing information to a manufacturing system	20010403 700/98
US 6205239 B1	System and method for circuit repair	20010320 382/149
US 6202043 B1	Computer based system for imaging and analyzing a process system and indicating values of process parameters	20010313 703/17
US 6198980 B1	System and method for designing a mixed-model manufacturing process	20010306 700/99
US 6192329 B1	Method and apparatus for assessing risks of injury	20010220 703/6
US 6185476 B1	Apparatus and method for managing and distributing design and manufacturing information to a manufacturing system	20010206 700/182
US 6173246 B1	Method and system for a unified process automation software system	20010109 703/22
US 6128986 A	Method and device for controlling a self-regulating, delayed process	20001003 702/127
US 6119125 A	Software components for a building automation system based on a standard object superclass	20000912 707/103R
US 6091846 A	Method and system for anomaly detection	20000718 382/145
US 6076048 A	System and method for least squares filtering based leak flow estimation/detection using expert knowledge	20000613 702/51
US 6065857 A	Computer readable medium for managing and distributing design and manufacturing information	20000523 700/95
US 6041263 A	Method and apparatus for simulating and optimizing a plant model	20000321 700/32
US 6014637 A	Object oriented framework mechanism for fulfillment requirements management	20000111 705/26
US 5990747 A	High frequency amplifier circuit and microwave integrated circuit	19991123 330/286
US 5980096 A	Computer-based system, methods and graphical interface for information storage, modeling and management	19991109 707/100
US 5973751 A	Variegated manufacturing process test method and apparatus	19991102 702/179
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US 5886897 A	Apparatus and method for managing and distributing design and manufacturing information through a hybrid linear-neural network process control	19990323 700/182
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US 5841660 A	Method and apparatus for modeling process control	19981124 700/115
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US 5640491 A	Control system using an adaptive neural network for target and path optimization for a multiviewer	19970617 706/25
US 5625552 A	Closed loop neural network automatic tuner	19970429 700/42
US 5621652 A	System and method for verifying process models in integrated circuit process simulators	19970415 716/5
US 5604892 A	Method for modeling a physical system of elements using a relational database	19970218 703/18
US 5579354 A	Method of measuring a corrosion potential, method of simulating potential characteristics of a metal	19961126 376/245
US 5560194 A	Method for optimally controlling fiber processing machines	19961001 57/264
US 5525552 A	Method for manufacturing test simulation in electronic circuit design	19960723 703/14
US 5504692 A	System and method for improved flow data reconciliation	19960402 700/266
US 5481475 A	Method of semiconductor device representation for fast and inexpensive simulations of seismic waves	19960102 716/20
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US 5382128 A	Apparatus and method for determining gradients of process variables	19940125 700/28
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US 3725653 A	APPARATUS FOR CONTROLLING CHEMICAL PROCESSES	19730403 700/29
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US 20060069541 A	Diagnostic method for actual process in manufacturing environment, involves determining dif	20060330
US 20050187745 A	Modeling, simulation, and analysis system for modifying model of biological process responsi	20050825
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US 6802045 B	Control simulation environment incorporating method for semiconductor manufacturing indu	20041005
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